

Special Issue

Holography, 3D Imaging and 3D Display

Message from the Guest Editors

Modern holographic techniques have been successfully applied in many important areas, such as 3D inspection, 3D microscopy, metrology and profilometry, augmented reality, and industrial informatics. This Special Issue covers selected pieces of cutting-edge research works, ranging from low-level acquisition, to the high-level analysis, processing, and manipulation of holographic information. The Special Issue also serves as a comprehensive review on the existing state-of-the-art techniques in 3D imaging and 3D display, as well as a broad insight into the future development of these disciplines. Your contributions toward the issue are greatly appreciated. If you have any questions regarding the Special Issue, please feel free to contact us.

Guest Editors

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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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